

Search Notes

Application No.

10/071,353

Examiner

Ali Bayat

Applicant(s)

TAKANO ET AL.

Art Unit

2625

SEARCHED

Class	Subclass	Date	Examiner
382	162,167,2 74,	1/4/2005 1/5/05	A.B
358	518-523		
	527		
345	589-591		
	593,601		
	604		
348	807,496		
	188,453		
	223.1		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Tran, Phuoc, Inventor name search; IEEE; EAST; US- PGPUB;USPAT;EPO;JPO;DERWENT ;IBM_TDB.	1/4/2005 1/5/05	A.B